DEC 13 2004 perwork Reduction

12-15-04

PTO/SB/30 (10-01)
Approved for use through 10/31/2002. OMB 0651-0031
U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

1995, no persons are required to respond to a collection of information unless it displays a valid OMB control number.

BADEMA REQUEST **FOR** 

## CONTINUED EXAMINATION (RCE) **TRANSMITTAL**

Address to: Mail Stop RCE Commissioner for Patents P.O. Box 1450

Alexandria, VA 22313-1450

Application Number	10/020,741		
Filing Date	December 12, 2001		
First Named Inventor	Dennison et al.		
Art Unit	2813		
Examiner Name	T. Nguyen		
Attorney Docket Number	2269-3259.1US (91-0473.02/RE)		

This is a Request for Continued Examination (RCE) under 37 CFR 1.114 of the above-identified application. Request for Continued Examination (RCE) practice under 37 CFR 1.114 does not apply to any utility or plant application filed prior to June 8, 1995, or to any design application. See Instruction Sheet for RCEs (not to be submitted to the USPTO) on page 2.

1. Submission required under 37 C.F.R. 1.114				
a. Previously submitted				
i. Consider the amendment(s)/reply under 37 C.F.R. 1.116 previously filed on				
(Any unentered amendment(s) referred to above will be entered).  ii. Consider the arguments in the Appeal Brief or Reply Brief previously filed on  iii. Other				
b. Enclosed	_			
	☐ Information☐ Other	Disclosure Statement	(IDS)	
2. Miscellaneous				
a. Suspension of action on the above-identified application is requested under 37 C.F.R. 1.103(c) for a period ofmonths. (Period of suspension shall not exceed 3 months; Fee under 37 C.F.R. 1.17(i) required)				
b.				
3. Fees The RCE fee under 37 C.F.R. 1.17(e) is required by 37 C.F.R. 1.114 when the RCE is filed.				
a. The Director is hereby authorized to charge any deficiency in the following fees, or credit any overpayments, to Deposit Account No. 20-1469				
i. Z RCE fee required under 37 C.F.R. 1.17(e)				
ii.				
b. Check in the amount of \$790.00 enclosed				
c. Payment by credit card (Form PTO-2038 enclosed				
WARNING: Information on this form may become public. Credit card information should not				
be included on this form. Provide credit card information and authorization on PTO-2038.				
SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT REQUIRED				
Name (Print /Type) Edgar R. Cataxinos	Registration No. (Attorney/Agent) 39,931			
Signature Plullulas	Date December 13, 2004			
CERTIFICATE OF MAILING				

Express Mail Label Number: EL994824290US

Date of Deposit: December 13, 2004 Person Making Deposit: Steve Wong

Burden Hour Statement: This form is estimated to take 0.2 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND Fees and Completed Forms to the following address: Mail Stop RCE, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.



## In re Application of:

Dennison et al.

Serial No.: 10/020,741

Filed: December 12, 2001

For: OPTIMIZED CONTAINER STACKED CAPACITOR DRAM CELL UTILIZING SACRIFICIAL OXIDE DEPOSITION AND CHEMICAL MECHANICAL POLISHING

Confirmation No.: 2283

Examiner: T. Nguyen

Group Art Unit: 2813

Attorney Docket No.: 2269-3259.1US

(91-0473.02/RE)

NOTICE OF EXPRESS MAILING

Express Mail Mailing Label Number: EL994824290US

Date of Deposit with USPS: December 13, 2004

Person making Deposit: Steve Wong

## AMENDMENT ACCOMPANYING REQUEST FOR CONTINUED EXAMINATION (RCE)

Mail Stop RCE Commissioner for Patents PO Box 1450 Alexandria, VA 22313-1450

Sir:

This Amendment is submitted simultaneously with a REQUEST FOR CONTINUED EXAMINATION. Prior to examination of the above-referenced patent application on the merits, entry of the amendments as set forth herein is respectfully solicited.

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 5 of this paper.